International Rectifier

Applications

- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

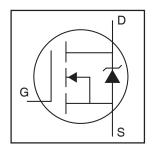
Benefits

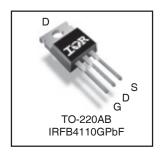
- Improved Gate, Avalanche and Dynamic dv/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free
- Halogen-Free

IRFB4110GPbF

HEXFET® Power MOSFET

V _{DSS}	100V
R _{DS(on)} typ.	$\mathbf{3.7m}\Omega$
max.	4.5m $Ω$
I _D (Silicon Limited)	180A ①
D (Package Limited)	120A





G	D	S
Gate	Drain	Source

Absolute Maximum Ratings

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, VGS @ 10V (Silicon Limited)	180①	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	130①	^
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Wire Bond Limited)	120	A
I _{DM}	Pulsed Drain Current ②	670	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	370	W
	Linear Derating Factor	2.5	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
dv/dt	Peak Diode Recovery ④	5.3	V/ns
T _J	Operating Junction and	-55 to + 175	
T_{STG}	Storage Temperature Range		-°C
	Soldering Temperature, for 10 seconds	300	
	(1.6mm from case)		
	Mounting torque, 6-32 or M3 screw	10lbf·in (1.1N·m)	
	- :		

Avalanche Characteristics

E _{AS (Thermally limited)}	Single Pulse Avalanche Energy ③	190	mJ
I _{AR}	Avalanche Current ②	See Fig. 14, 15, 22a, 22b	Α
E _{AR}	Repetitive Avalanche Energy ②		mJ

Thermal Resistance

Thermal nesistance									
Symbol	Parameter	Тур.	Max.	Units					
$R_{\theta JC}$	Junction-to-Case ®		0.402						
$R_{\theta CS}$	Case-to-Sink, Flat Greased Surface	0.50		°C/W					
$R_{\theta JA}$	Junction-to-Ambient		62						

Static @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.108		V/°C	Reference to 25°C, I _D = 5mA ^②
R _{DS(on)}	Static Drain-to-Source On-Resistance		3.7	4.5	mΩ	$V_{GS} = 10V, I_D = 75A$ ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
I _{DSS}	Drain-to-Source Leakage Current			20		$V_{DS} = 100V, V_{GS} = 0V$
				250	μA	$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I_{GSS}	Gate-to-Source Forward Leakage			100	n^	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-100	nA	$V_{GS} = -20V$

Dynamic @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	160			S	$V_{DS} = 50V, I_{D} = 75A$
Q_g	Total Gate Charge		150	210		I _D = 75A
Q_{gs}	Gate-to-Source Charge		35		nC	$V_{DS} = 50V$
Q_{gd}	Gate-to-Drain ("Miller") Charge		43			V _{GS} = 10V ⑤
R _G	Gate Resistance		1.3		Ω	
t _{d(on)}	Turn-On Delay Time		25			$V_{DD} = 65V$
t _r	Rise Time		67			I _D = 75A
t _{d(off)}	Turn-Off Delay Time		78		ns	$R_G = 2.6\Omega$
t _f	Fall Time		88			V _{GS} = 10V ⑤
C _{iss}	Input Capacitance		9620			$V_{GS} = 0V$
C _{oss}	Output Capacitance		670			$V_{DS} = 50V$
C _{rss}	Reverse Transfer Capacitance		250		рF	f = 1.0MHz
C _{oss} eff. (ER)	Effective Output Capacitance (Energy Related)		820			$V_{GS} = 0V$, $V_{DS} = 0V$ to $80V$ \bigcirc
C _{oss} eff. (TR)	Effective Output Capacitance (Time Related) ®		950			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 80V $

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			170①		MOSFET symbol
	(Body Diode)				_	showing the
I _{SM}	Pulsed Source Current			670	Α	integral reverse
	(Body Diode) ②					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 75A, V_{GS} = 0V $ ⑤
t _{rr}	Reverse Recovery Time		50	75		$T_J = 25^{\circ}C$ $V_R = 85V$,
			60	90	ns	$T_J = 125^{\circ}C$ $I_F = 75A$
Q _{rr}	Reverse Recovery Charge		94	140	_ ~_	$T_J = 25^{\circ}C$ di/dt = 100A/ μ s \odot
			140	210		$T_J = 125^{\circ}C$
I _{RRM}	Reverse Recovery Current		3.5		Α	$T_J = 25^{\circ}C$
t _{on}	Forward Turn-On Time	Intrins	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

Notes:

- ① Calculated continuous current based on maximum allowable junction ④ $I_{SD} \le 75A$, $di/dt \le 630A/\mu s$, $V_{DD} \le V_{(BR)DSS}$, $T_{J} \le 175^{\circ}C$. temperature. Bond wire current limit is 120A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- $R_G = 25\Omega$, $I_{AS} = 108A$, $V_{GS} = 10V$. Part not recommended for use above this value.
- ⑤ Pulse width $\leq 400\mu s$; duty cycle $\leq 2\%$.
- as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- O Coss eff. (ER) is a fixed capacitance that gives the same energy as $C_{oss}\,\text{while}\,\,V_{DS}\,\text{is rising from 0 to 80\%}\,\,V_{DSS}.$
- $\$ R_{θ} is measured at T_J approximately 90°C.

2 www.irf.com

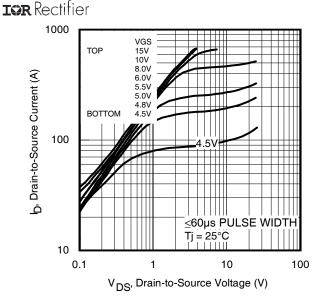


Fig 1. Typical Output Characteristics

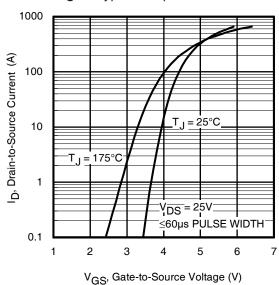


Fig 3. Typical Transfer Characteristics

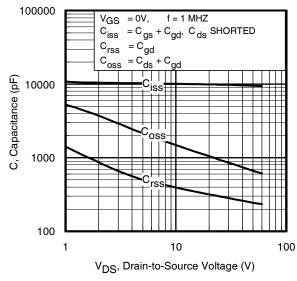


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage www.irf.com

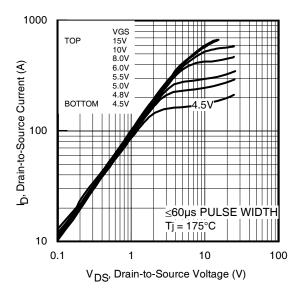


Fig 2. Typical Output Characteristics

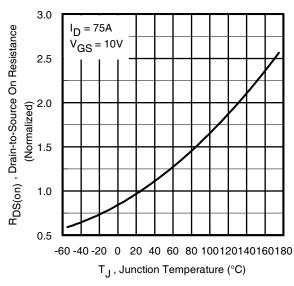


Fig 4. Normalized On-Resistance vs. Temperature

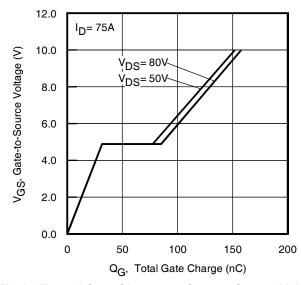


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

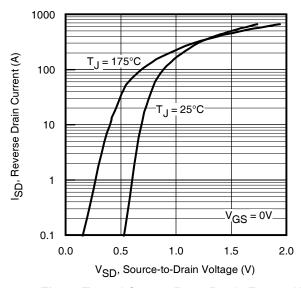


Fig 7. Typical Source-Drain Diode Forward Voltage

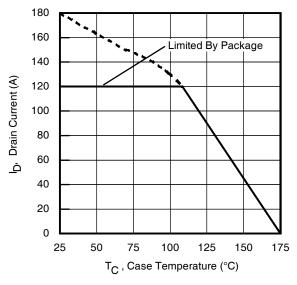


Fig 9. Maximum Drain Current vs. Case Temperature

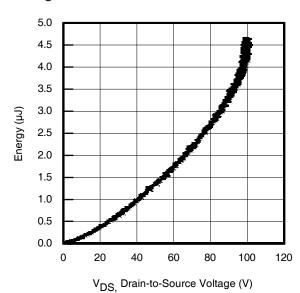


Fig 11. Typical C_{OSS} Stored Energy

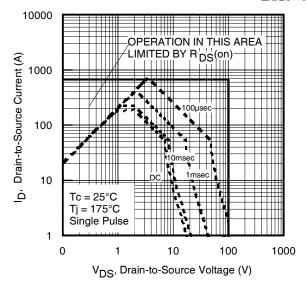


Fig 8. Maximum Safe Operating Area

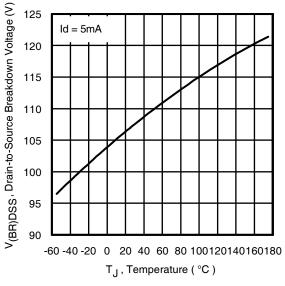


Fig 10. Drain-to-Source Breakdown Voltage

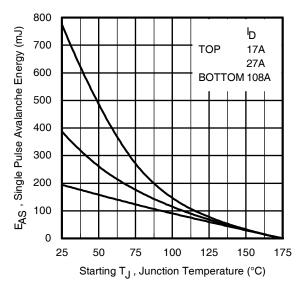


Fig 12. Maximum Avalanche Energy vs. DrainCurrent www.irf.com

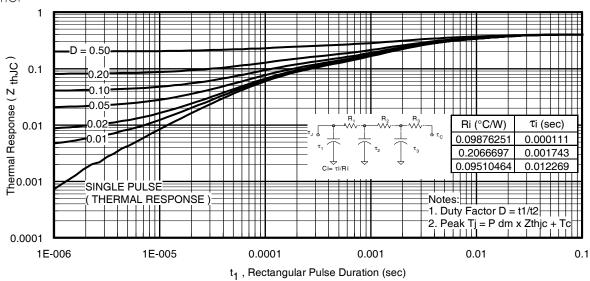


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

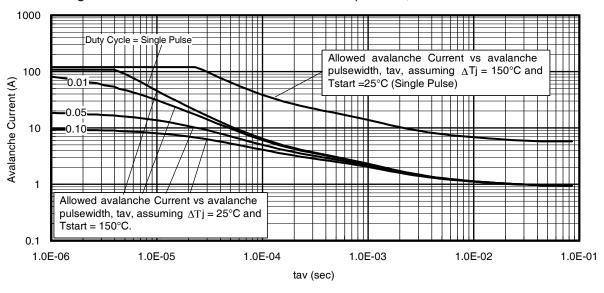


Fig 14. Typical Avalanche Current vs. Pulsewidth

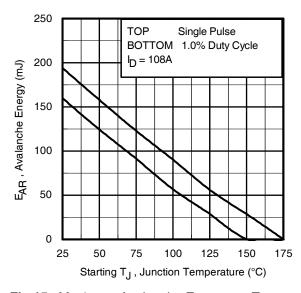


Fig 15. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption:
- Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT_{imax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.
- 4. $P_{D (ave)}$ = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).
 - t_{av =} Average time in avalanche.
 - D = Duty cycle in avalanche = $t_{av} \cdot f$

 $Z_{th,JC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \triangle T / \; Z_{thJC} \\ I_{av} &= 2\triangle T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

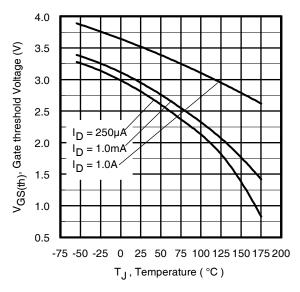


Fig 16. Threshold Voltage vs. Temperature

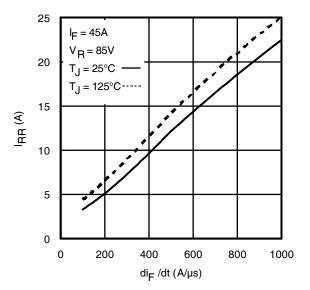


Fig. 18 - Typical Recovery Current vs. dif/dt

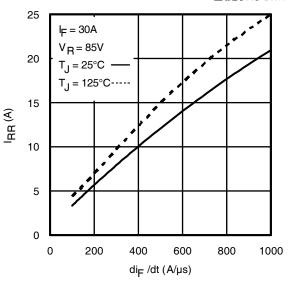


Fig. 17 - Typical Recovery Current vs. dif/dt

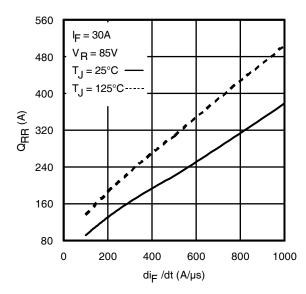


Fig. 19 - Typical Stored Charge vs. di_f/dt

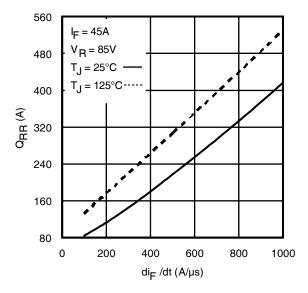


Fig. 20 - Typical Stored Charge vs. dif/dt

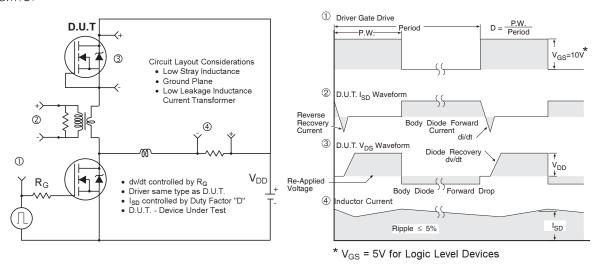


Fig 20. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

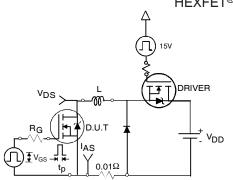


Fig 21a. Unclamped Inductive Test Circuit

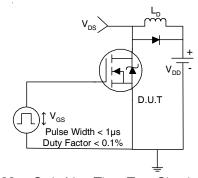


Fig 22a. Switching Time Test Circuit

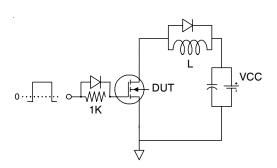


Fig 23a. Gate Charge Test Circuit

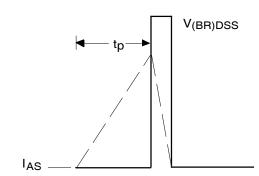


Fig 21b. Unclamped Inductive Waveforms

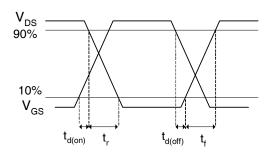


Fig 22b. Switching Time Waveforms

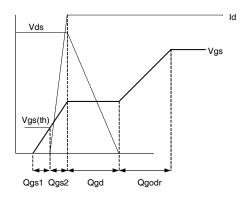
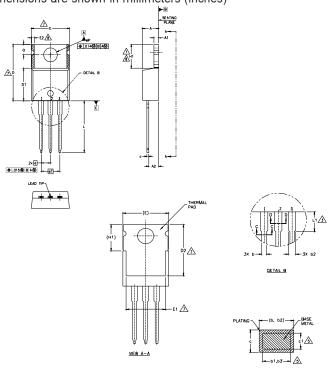


Fig 23b. Gate Charge Waveform

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



NOTES:

- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994
- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
- DMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH
 SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE
 MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY. CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC 10-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

	DIMENSIONS						
1							
SYMBOL	MILLIM	ETERS	INC	HES			
	MIN.	MAX.	MIN.	MAX.	NOTES		
Α	3,56	4.83	.140	.190			
A1	0.51	1,40	.020	.055			
A2	2.03	2.92	.080	.115			
b	0.38	1,01	.015	.040			
ь1	0.38	0.97	.015	.038	5		
b2	1,14	1.78	.045	.070			
b3	1,14	1.73	.045	.068	5		
С	0.36	0.61	.014	.024			
c1	0.36	0.56	.014	.022	5		
D	14.22	16.51	.560	.650	4		
D1	8.38	9.02	.330	.355			
D2	11,68	12.88	.460	.507	7		
E	9.65	10.67	.380	.420	4,7		
E1	6.86	8.89	.270	.350	7		
E2	-	0.76	-	.030	8		
e	2.54	2.54 BSC		BSC			
e1	5.08	BSC	.200 BSC				
H1	5,84	6.86	.230	.270	7,8		
L	12.70	14.73	.500	.580			
L1	3.56	4.06	.140	.160	3		
øΡ	3,54	4.08	.139	.161			
Q	2,54	3.42	.100	,135			

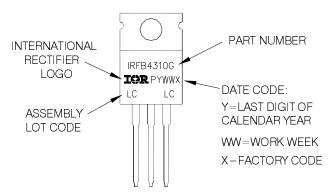
LEAD ASSIGNMENTS HEXFET 1.- GATE 2.- DRAIN 3.- SOURCE IGBTs. CoPACK 1.- GATE 2.- COLLECTOR 3.- EMITTER DIODES

TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRFB4310GPBF

Note: "G" suffix in part number indicates "Halogen - Free"

Note: "P" in assembly line position indicates "Lead - Free"



TO-220AB packages are not recommended for Surface Mount Application.

Note: For the most current drawing please refer to IR website at: http://www.irf.com/package/

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



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TAC Fax: (310) 252-7903

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